Electronic Supporting Information (ESI)

Bacterial viability on chemically modified silicon nanowire arrays

A. Susarrey-Arce, ^{*a} I. Sorzabal-Bellido, ^a A. Oknianska, ^a F. McBride, ^a A. J. Beckett, ^b J. G. E. Gardeniers, ^c R. Raval, ^{*a} R. M. Tiggelaar, ^{*c, d} Y. A. Diaz Fernandez, ^{*a}

^{a.} Open Innovation Hub for Antimicrobial Surfaces at the Surface Science Research Centre and Department of Chemistry, University of Liverpool, Oxford Street, UK L69 3BX, Liverpool

^{b.}Biomedical EM Unit, School of Biomedical Sciences, Crown Street, University of Liverpool, L69 3BX, Liverpool

^c Mesoscale Chemical Systems, MESA+ Institute for Nanotechnology, University of Twente, P.O. Box 217, 7500AE Enschede, The Netherlands

^{d.}NanoLab Cleanroom, MESA+ Institute for Nanotechnology, University of Twente, P.O. Box 217, 7500AE Enschede, The Netherlands

ESI Index

1. Analysis of SiNWs surface

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1.1	SiNWs	surface	analysis	with	XPS

- 1.2 Contact Angle Measurements on SiNWs
- 2. Analysis of bacterial morphology on SiNWs surfaces

	2.1. E. coli colonization on flat silicon surfaces	2
	2.2. S. aureus colonization on non-functionalised SiNWs arrays	3
	2.3. S. aureus colonization on flat silicon surfaces	3
3 UV-Vis	s calibration curve for chlorhexidine (CHD) digluconate	4
4. SiNW	's-APTES surfaces with low loading of chlorhexidine (CHD) digluconate	5
5. Bacte	eria viability tests at SiNWs surfaces (live/dead assays)	6

1

1

1. Analysis of SiNWs surface





Figure S1: XPS spectra of SiNWs surface.

1.2 Contact Angle Measurements on SiNWs

CA-measurements are carried out on a Dataphysics OCA-20 contact angle system (2 μ l DI-water droplet, sessile mode). Average values for 3 measurements for each sample/configuration are reported.



Figure S2: CA-images on SiNWs as synthetized (20 min MACE) and after overnight cleaning with nitric acid.

Table S1.	Physical	chemical	properties	of silicon	nanowires
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Surface	SiNWs	bSi [¥] as-etched	bSi [¥] after removal fluorocarbon residue	
Contact angle+	5°	80°	38°	
O/Si ratio ^{&}	64.3:32.3	7.0:15.5	27.8:28.1 to 57.7:35.0	
F-content [%] ^{&}	0.24	51.2	3.8 to 28.2	
Diameter	143 ± 24 nm	50-250 nm	50-250 nm	
Interspacing ^T	77 nm ± 16 nm	60-300 nm	60-300 nm	
Height	11.3 ± 0.2 µm	450-850 nm	450-850 nm	
¥fabricated black-silicon following Ivanova et al. Nature Communications (2013) 4, 2838; ⁺with DI-water, &based on XPS				
analysis; ^T between adjacent nanostructures				

Some SiNWs properties are shown in table S1. We have compared SiNWs substrates with two homemade black silicon surfaces (bSi): (1) as-etched and (2) after removal of fluorocarbon residue. These samples were fabricated by using deep reactive ion etching (DRIE) using a Bosch-process (i.e. SF₆ and C₄F₈ as etch and passivation gasses) as reported by Ivanova *et al. Nature Communications* (2013) 4, 2838. As-etched bSi surfaces show a contact angle (CA) of 80°, which reduced to ~ 38° after removal of fluorocarbon residue remaining from the DRIE-process (due to dissolvation of fluor traces). Elemental analysis of nanowire-surfaces, display a (much) lower O/Si ratio for the bSi-samples (in particular prior to fluorocarbon removal) in comparison with the SiNWs-surface. These results confirm that accurate chemical characterization of the surface is important for the interpretation of wettability experiments.

2. Analysis of bacterial morphology on SiNWs surfaces

2.1. E. coli colonization on flat silicon surfaces



Figure S3. Representative SEM image of *E. coli* colonization of flat silicon surface after 8h culture.

2.2. S. aureus colonization on non-functionalised SiNWs arrays



Figure S4. Representative SEM image of *S. aureus* on SiNWs after 8h of culture. *S. aureus* reveals vertical development of the colonies.



2.3. S. aureus colonization on flat silicon surfaces

Figure S5. Representative SEM images of *S. aureus* colonization of flat silicon surface after 8h culture.

3. UV-Vis calibration curve for chlorhexidine (CHD) digluconate



Figure S6. (a) UV-Vis spectra of different concentrations of CHD in water. (b) Calibration curve of CHD at λ = 255 nm.

4. SiNWs-APTES surfaces with low loading of chlorhexidine (CHD) digluconate



Figure S7. Representative SEM images of *S. aureus* on SiNWs functionalised with APTES and chlorhexidine (CHD) digluconate with loading concentration of 0.002% after different culture times: (a) 8 h (b) 24 h



Figure S8. Representative SEM image of *E. coli* on SiNWs functionalised with APTES and chlorhexidine (CHD) digluconate with loading concentration 0.02% at 24 h, showing no recolonization.

5. Bacteria viability tests at surfaces (live/dead assays)



Figure S9. Representative confocal microscopy images of live (green) and dead (red) *E. coli* after 8h of culture on different surfaces: (a, f) SiNWs, (b, g) SiNWs-APTES, (c, h) SiNWs-APTES loaded with 0.02% CHD and (e, i) SiNWs-APTES loaded with 0.002% CHD



Figure S10. Representative confocal microscopy images of live (green) and dead (red) *S. aureus* after 8h of culture on different surfaces: (a, f) SiNWs, (b, g) SiNWs-APTES, (c, h) SiNWs-APTES loaded with 0.02% CHD and (e, i) SiNWs-APTES loaded with 0.002% CHD